

## Product Description

Calibration grating TDG01 is intended for AFM submicron calibration in X or Y direction. Period is 278nm.

### General Features

Structure	the grating is formed on the chalcogenide glass coated by Al
Pattern type	parallel ridges in X or Y direction, 1-Dimensional
Period	278 ± 1 nm
Height	> 55 nm
Chip size	diameter 12,5 mm, thickness - 2,5 mm
Effective area	central diameter 9 mm